Search Notes		

Application/Control No.	Applicant(s)/Patent unde Reexamination	r
10/038,906	CHEN ET AL.	
Examiner	Art Unit	
Scott L. Jarrett	3623	

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SEARCH I (INCLUDING SEAR	NOTES CH STRATEGY)
	DATE	EXMR
East - JP, EP, US see attached search history	4/14/2006	SJ
ProQuest see attached search history	4/14/2006	SJ